E·XFL



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	6144
Total RAM Bits	36864
Number of I/O	68
Number of Gates	250000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/agl250v2-vq100i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Flash*Freeze Technology

The IGLOO device has an ultra-low power static mode, called Flash*Freeze mode, which retains all SRAM and register information and can still quickly return to normal operation. Flash*Freeze technology enables the user to quickly (within 1 µs) enter and exit Flash*Freeze mode by activating the Flash*Freeze pin while all power supplies are kept at their original values. In addition, I/Os and global I/Os can still be driven and can be toggling without impact on power consumption, clocks can still be driven or can be toggling without impact on power consumption, and the device retains all core registers, SRAM information, and states. I/O states are tristated during Flash*Freeze mode or can be set to a certain state using weak pull-up or pull-down I/O attribute configuration. No power is consumed by the I/O banks, clocks, JTAG pins, or PLL, and the device consumes as little as 5 µW in this mode.

Flash*Freeze technology allows the user to switch to active mode on demand, thus simplifying the power management of the device.

The Flash*Freeze pin (active low) can be routed internally to the core to allow the user's logic to decide when it is safe to transition to this mode. It is also possible to use the Flash*Freeze pin as a regular I/O if Flash*Freeze mode usage is not planned, which is advantageous because of the inherent low power static (as low as 12 μ W) and dynamic capabilities of the IGLOO device. Refer to Figure 1-3 for an illustration of entering/exiting Flash*Freeze mode.

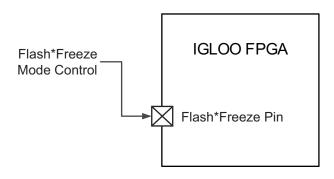


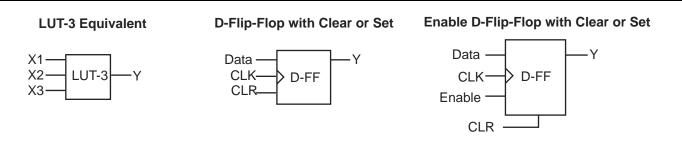
Figure 1-3 • IGLOO Flash*Freeze Mode

VersaTiles

The IGLOO core consists of VersaTiles, which have been enhanced beyond the ProASIC^{PLUS®} core tiles. The IGLOO VersaTile supports the following:

- All 3-input logic functions—LUT-3 equivalent
- Latch with clear or set
- D-flip-flop with clear or set
- Enable D-flip-flop with clear or set

Refer to Figure 1-4 for VersaTile configurations.



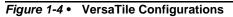


Table 2-20 • Different Components Contributing to the Static Power Consumption in IGLOO Devices For IGLOO V2 or V5 Devices, 1.5 V DC Core Supply Voltage

			Device-Specific Static Power (mW)											
Parameter	Definition	AGL1000	AGL600	AGL400	AGL250	AGL125	AGL060	AGL030	AGL015					
PDC1	Array static power in Active mode			See	Table 2-12	2 on page 2	2-9.							
PDC2	Array static power in Static (Idle) mode			See	Table 2-11	on page 2	2-8.							
PDC3	Array static power in Flash*Freeze mode			See	e Table 2-9	on page 2	-7.							
PDC4	Static PLL contribution				1.8	34								
PDC5	Bank quiescent power (V _{CCI} -dependent)			See	Table 2-12	2 on page 2	2-9.							
PDC6	I/O input pin static power (standard-dependent)		See Table	2-13 on pa	ige 2-10 thi	rough Table	e 2-15 on p	age 2-11.						
PDC7	I/O output pin static power (standard-dependent)		See Table	2-16 on pa	ige 2-11 thr	ough Table	e 2-18 on p	age 2-12.						

Note: *For a different output load, drive strength, or slew rate, Microsemi recommends using the Microsemi power spreadsheet calculator or SmartPower tool in Libero SoC.

Power Calculation Methodology

This section describes a simplified method to estimate power consumption of an application. For more accurate and detailed power estimations, use the SmartPower tool in Microsemi Libero SoC software.

The power calculation methodology described below uses the following variables:

- The number of PLLs as well as the number and the frequency of each output clock generated
- The number of combinatorial and sequential cells used in the design
- The internal clock frequencies
- The number and the standard of I/O pins used in the design
- The number of RAM blocks used in the design
- Toggle rates of I/O pins as well as VersaTiles—guidelines are provided in Table 2-23 on page 2-19.
- Enable rates of output buffers—guidelines are provided for typical applications in Table 2-24 on page 2-19.
- Read rate and write rate to the memory—guidelines are provided for typical applications in Table 2-24 on page 2-19. The calculation should be repeated for each clock domain defined in the design.

Methodology

Total Power Consumption—P_{TOTAL}

 $P_{TOTAL} = P_{STAT} + P_{DYN}$

 $\mathsf{P}_{\mathsf{STAT}}$ is the total static power consumption.

P_{DYN} is the total dynamic power consumption.

Total Static Power Consumption—PSTAT

P_{STAT} = (P_{DC1} or P_{DC2} or P_{DC3}) + N_{BANKS} * P_{DC5} + N_{INPUTS} * P_{DC6} + N_{OUTPUTS} * P_{DC7}

N_{INPUTS} is the number of I/O input buffers used in the design.

N_{OUTPUTS} is the number of I/O output buffers used in the design.

N_{BANKS} is the number of I/O banks powered in the design.

Total Dynamic Power Consumption—PDYN

 $P_{DYN} = P_{CLOCK} + P_{S-CELL} + P_{C-CELL} + P_{NET} + P_{INPUTS} + P_{OUTPUTS} + P_{MEMORY} + P_{PLL}$

Global Clock Contribution—P_{CLOCK}

 $\mathsf{P}_{\mathsf{CLOCK}} = (\mathsf{P}_{\mathsf{AC1}} + \mathsf{N}_{\mathsf{SPINE}} * \mathsf{P}_{\mathsf{AC2}} + \mathsf{N}_{\mathsf{ROW}} * \mathsf{P}_{\mathsf{AC3}} + \mathsf{N}_{\mathsf{S}\text{-}\mathsf{CELL}} * \mathsf{P}_{\mathsf{AC4}}) * \mathsf{F}_{\mathsf{CLK}}$

N_{SPINE} is the number of global spines used in the user design—guidelines are provided in the "Spine Architecture" section of the *IGLOO FPGA Fabric User Guide.*

N_{ROW} is the number of VersaTile rows used in the design—guidelines are provided in the "Spine Architecture" section of the *IGLOO FPGA Fabric User Guide*.

 $\mathsf{F}_{\mathsf{CLK}}$ is the global clock signal frequency.

N_{S-CELL} is the number of VersaTiles used as sequential modules in the design.

P_{AC1}, P_{AC2}, P_{AC3}, and P_{AC4} are device-dependent.

Sequential Cells Contribution—P_{S-CELL}

 $\mathsf{P}_{\text{S-CELL}} = \mathsf{N}_{\text{S-CELL}} * (\mathsf{P}_{\text{AC5}} + \alpha_1 / 2 * \mathsf{P}_{\text{AC6}}) * \mathsf{F}_{\text{CLK}}$

 N_{S-CELL} is the number of VersaTiles used as sequential modules in the design. When a multi-tile sequential cell is used, it should be accounted for as 1.

 α_1 is the toggle rate of VersaTile outputs—guidelines are provided in Table 2-23 on page 2-19.

 F_{CLK} is the global clock signal frequency.

User I/O Characteristics

Timing Model

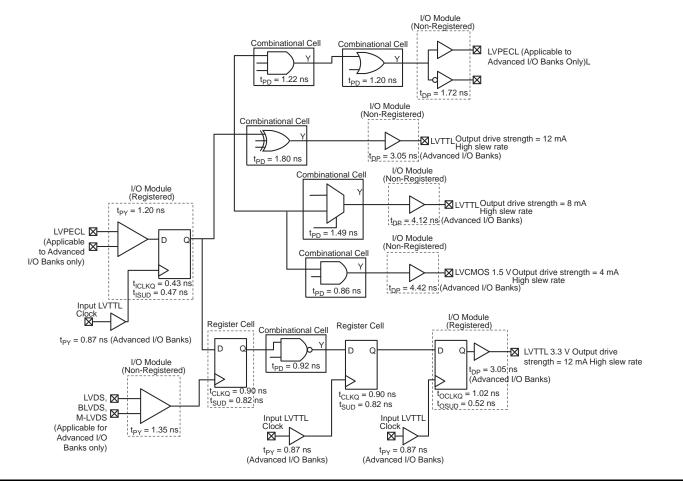


Figure 2-3 • Timing Model

Operating Conditions: Std. Speed, Commercial Temperature Range ($T_J = 70^{\circ}$ C), Worst-Case VCC = 1.425 V, for DC 1.5 V Core Voltage, Applicable to V2 and V5 Devices

Summary of I/O Timing Characteristics – Default I/O Software Settings

Table 2-29 • Summary of AC Measuring Points

Standard	Measuring Trip Point (Vtrip)
3.3 V LVTTL / 3.3 V LVCMOS	1.4 V
3.3 V VCMOS Wide Range	1.4 V
2.5 V LVCMOS	1.2 V
1.8 V LVCMOS	0.90 V
1.5 V LVCMOS	0.75 V
1.2 V LVCMOS	0.60 V
1.2 V LVCMOS Wide Range	0.60 V
3.3 V PCI	0.285 * VCCI (RR)
	0.615 * VCCI (FF)
3.3 V PCI-X	0.285 * VCCI (RR)
	0.615 * VCCI (FF)

Table 2-30 • I/O AC Parameter Definitions

Parameter	Parameter Definition
t _{DP}	Data to Pad delay through the Output Buffer
t _{PY}	Pad to Data delay through the Input Buffer
t _{DOUT}	Data to Output Buffer delay through the I/O interface
t _{EOUT}	Enable to Output Buffer Tristate Control delay through the I/O interface
t _{DIN}	Input Buffer to Data delay through the I/O interface
t _{HZ}	Enable to Pad delay through the Output Buffer—High to Z
t _{ZH}	Enable to Pad delay through the Output Buffer—Z to High
t _{LZ}	Enable to Pad delay through the Output Buffer—Low to Z
t _{ZL}	Enable to Pad delay through the Output Buffer—Z to Low
t _{ZHS}	Enable to Pad delay through the Output Buffer with delayed enable—Z to High
t _{ZLS}	Enable to Pad delay through the Output Buffer with delayed enable—Z to Low

Detailed I/O DC Characteristics

Table 2-37 • Input Capacitance

Symbol	Definition	Conditions	Min.	Max.	Units
C _{IN}	Input capacitance	VIN = 0, f = 1.0 MHz		8	pF
CINCLK	Input capacitance on the clock pin	VIN = 0, f = 1.0 MHz		8	pF

Table 2-38 • I/O Output Buffer Maximum Resistances¹ Applicable to Advanced I/O Banks

Standard	Drive Strength	R _{PULL-DOWN} (Ω) ²	R _{PULL-UP} (Ω) ³
3.3 V LVTTL / 3.3 V LVCMOS	2 mA	100	300
	4 mA	100	300
	6 mA	50	150
	8 mA	50	150
	12 mA	25	75
	16 mA	17	50
	24 mA	11	33
3.3 V LVCMOS Wide Range	100 μA	Same as regular 3.3 V LVCMOS	Same as regular 3.3 V LVCMOS
2.5 V LVCMOS	2 mA	100	200
	4 mA	100	200
	6 mA	50	100
	8 mA	50	100
	12 mA	25	50
	16 mA	20	40
1.5 V LVCMOS	2 mA	200	224
	4 mA	100	112
	6 mA	67	75
	8 mA	33	37
	12 mA	33	37
1.2 V LVCMOS ⁴	2 mA	158	164
1.2 V LVCMOS Wide Range ⁴	100 μA	Same as regular 1.2 V LVCMOS	Same as regular 1.2 V LVCMOS
3.3 V PCI/PCI-X	Per PCI/PCI-X specification	25	75

Notes:

1. These maximum values are provided for informational reasons only. Minimum output buffer resistance values depend on VCCI, drive strength selection, temperature, and process. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located at http://www.microsemi.com/soc/download/ibis/default.aspx.

2. R_(PULL-DOWN-MAX) = (VOLspec) / I_{OLspec}

3. R_(PULL-UP-MAX) = (VCCImax – VOHspec) / I_{OHspec}

4. Applicable to IGLOO V2 Devices operating at VCCI ≥ VCC

Table 2-60 • 3.3 V LVTTL / 3.3 V LVCMOS High Slew – Applies to 1.2 V DC Core VoltageCommercial-Case Conditions: TJ = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 3.0 VApplicable to Standard Plus Banks

Drive Strength	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{zHS}	Units
2 mA	Std.	1.55	2.89	0.26	0.97	1.10	2.93	2.38	2.53	2.96	8.72	8.17	ns
4 mA	Std.	1.55	2.89	0.26	0.97	1.10	2.93	2.38	2.53	2.96	8.72	8.17	ns
6 mA	Std.	1.55	2.50	0.26	0.97	1.10	2.54	2.04	2.77	3.37	8.33	7.82	ns
8 mA	Std.	1.55	2.50	0.26	0.97	1.10	2.54	2.04	2.77	3.37	8.33	7.82	ns
12 mA	Std.	1.55	2.31	0.26	0.97	1.10	2.34	1.86	2.93	3.64	8.12	7.65	ns
16 mA	Std.	1.55	2.31	0.26	0.97	1.10	2.34	1.86	2.93	3.64	8.12	7.65	ns

Notes:

1. Software default selection highlighted in gray.

2. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-61 • 3.3 V LVTTL / 3.3 V LVCMOS Low Slew – Applies to 1.2 V DC Core Voltage Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 3.0 V Applicable to Standard Banks

Drive Strength	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	Units
2 mA	Std.	1.55	4.39	0.26	0.94	1.10	4.46	3.91	2.17	2.44	ns
4 mA	Std.	1.55	4.39	0.26	0.94	1.10	4.46	3.91	2.17	2.44	ns
6 mA	Std.	1.55	3.72	0.26	0.94	1.10	3.78	3.43	2.40	2.85	ns
8 mA	Std.	1.55	3.72	0.26	0.94	1.10	3.78	3.43	2.40	2.85	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Table 2-62 • 3.3 V LVTTL / 3.3 V LVCMOS High Slew – Applies to 1.2 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^{\circ}$ C, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 3.0 V Applicable to Standard Banks

Drive Strength	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	Units
2 mA	Std.	1.55	2.74	0.26	0.94	1.10	2.78	2.26	2.17	2.55	ns
4 mA	Std.	1.55	2.74	0.26	0.94	1.10	2.78	2.26	2.17	2.55	ns
6 mA	Std.	1.55	2.38	0.26	0.94	1.10	2.41	1.92	2.40	2.96	ns
8 mA	Std.	1.55	2.38	0.26	0.94	1.10	2.41	1.92	2.40	2.96	ns

Notes:

1. Software default selection highlighted in gray.

2. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

Timing Characteristics

Applies to 1.5 V DC Core Voltage

Table 2-83 •2.5 V LVCMOS Low Slew – Applies to 1.5 V DC Core Voltage
Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V
Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
2 mA	Std.	0.97	4.96	0.18	1.08	0.66	5.06	4.59	2.26	2.00	8.66	8.19	ns
4 mA	Std.	0.97	4.96	0.18	1.08	0.66	5.06	4.59	2.26	2.00	8.66	8.19	ns
6 mA	Std.	0.97	4.15	0.18	1.08	0.66	4.24	3.94	2.54	2.51	7.83	7.53	ns
8 mA	Std.	0.97	4.15	0.18	1.08	0.66	4.24	3.94	2.54	2.51	7.83	7.53	ns
12 mA	Std.	0.97	3.57	0.18	1.08	0.66	3.65	3.47	2.73	2.84	7.24	7.06	ns
16 mA	Std.	0.97	3.39	0.18	1.08	0.66	3.46	3.36	2.78	2.92	7.06	6.95	ns
24 mA	Std.	0.97	3.38	0.18	1.08	0.66	3.38	3.38	2.83	3.25	6.98	6.98	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-84 • 2.5 V LVCMOS High Slew – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: $T_J = 70^{\circ}$ C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
2 mA	Std.	0.97	2.77	0.18	1.08	0.66	2.83	2.60	2.26	2.08	6.42	6.19	ns
4 mA	Std.	0.97	2.77	0.18	1.08	0.66	2.83	2.60	2.26	2.08	6.42	6.19	ns
6 mA	Std.	0.97	2.34	0.18	1.08	0.66	2.39	2.08	2.54	2.60	5.99	5.68	ns
8 mA	Std.	0.97	2.34	0.18	1.08	0.66	2.39	2.08	2.54	2.60	5.99	5.68	ns
12 mA	Std.	0.97	2.09	0.18	1.08	0.66	2.14	1.83	2.73	2.93	5.73	5.43	ns
16 mA	Std.	0.97	2.05	0.18	1.08	0.66	2.09	1.78	2.78	3.02	5.69	5.38	ns
24 mA	Std.	0.97	2.06	0.18	1.08	0.66	2.10	1.72	2.83	3.35	5.70	5.32	ns

Notes:

1. Software default selection highlighted in gray.

2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-85 •2.5 V LVCMOS Low Slew – Applies to 1.5 V DC Core Voltage
Commercial-Case Conditions: TJ = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V
Applicable to Standard Plus Banks

Drive Strength	Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
2 mA	Std.	0.97	4.42	0.18	1.08	0.66	4.51	4.10	1.96	1.85	8.10	7.69	ns
4 mA	Std.	0.97	4.42	0.18	1.08	0.66	4.51	4.10	1.96	1.85	8.10	7.69	ns
6 mA	Std.	0.97	3.62	0.18	1.08	0.66	3.70	3.52	2.21	2.32	7.29	7.11	ns
8 mA	Std.	0.97	3.62	0.18	1.08	0.66	3.70	3.52	2.21	2.32	7.29	7.11	ns
12 mA	Std.	0.97	3.09	0.18	1.08	0.66	3.15	3.09	2.39	2.61	6.74	6.68	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

1.2 V LVCMOS (JESD8-12A)

Low-Voltage CMOS for 1.2 V complies with the LVCMOS standard JESD8-12A for general purpose 1.2 V applications. It uses a 1.2 V input buffer and a push-pull output buffer. Furthermore, all LVCMOS 1.2 V software macros comply with LVCMOS 1.2 V wide range as specified in the JESD8-12A specification.

Table 2-127 • Minimum and Maximum DC Input and Output Levels Applicable to Advanced I/O Banks

1.2 V LVCMOS		VIL	VIH		VOL	VOH	IOL	юн	IOSH	IOSL	IIL ¹	IIH ²
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μA ⁴	μA ⁴
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.26	0.25 * VCCI	0.75 * VCCI	2	2	20	26	10	10

Notes:

1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.

- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 3. Currents are measured at 100°C junction temperature and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.

Table 2-128 • Minimum and Maximum DC Input and Output Levels Applicable to Standard Plus I/O Banks

1.2 V LVCMOS		VIL	VIH		VOL	VOH	I _{OL}	юн	IOSH	IOSL	IIL ¹	IIH ²
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μA ⁴	μA ⁴
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	1.26	0.25 * VCCI	0.75 * VCCI	2	2	20	26	10	10

Notes:

- 1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 3. Currents are measured at 100°C junction temperature and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.

Table 2-129 • Minimum and Maximum DC Input and Output Levels Applicable to Standard I/O Banks

1.2 V LVCMOS		VIL	VIH		VOL	VOH	IOL	юн	IOSH	IOSL	IIL¹	IIH ²
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μA ⁴	μA ⁴
1 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	1	1	20	26	10	10

Notes:

1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.

2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges

3. Currents are measured at 100°C junction temperature and maximum voltage.

4. Currents are measured at 85°C junction temperature.

5. Software default selection highlighted in gray.

DDR Module Specifications

Input DDR Module

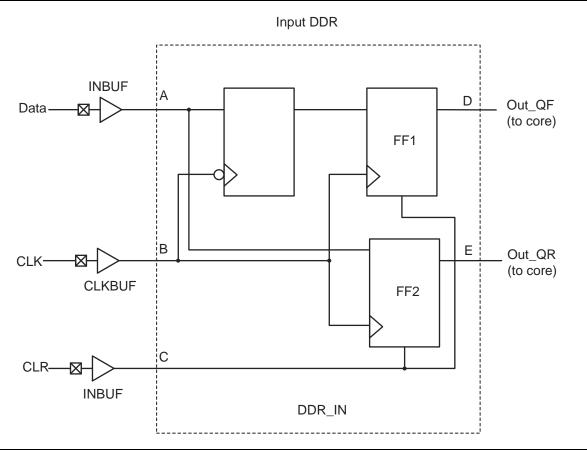


Figure 2-21 • Input DDR Timing Model

Table 2-163 • F	Parameter	Definitions
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Parameter Name	Parameter Definition	Measuring Nodes (from, to)
t _{DDRICLKQ1}	Clock-to-Out Out_QR	B, D
tDDRICLKQ2	Clock-to-Out Out_QF	B, E
tDDRISUD	Data Setup Time of DDR input	А, В
	Data Hold Time of DDR input	A, B
t _{DDRICLR2Q1}	Clear-to-Out Out_QR	C, D
t _{DDRICLR2Q2}	Clear-to-Out Out_QF	C, E
t _{DDRIREMCLR}	Clear Removal	С, В
t _{DDRIRECCLR}	Clear Recovery	С, В

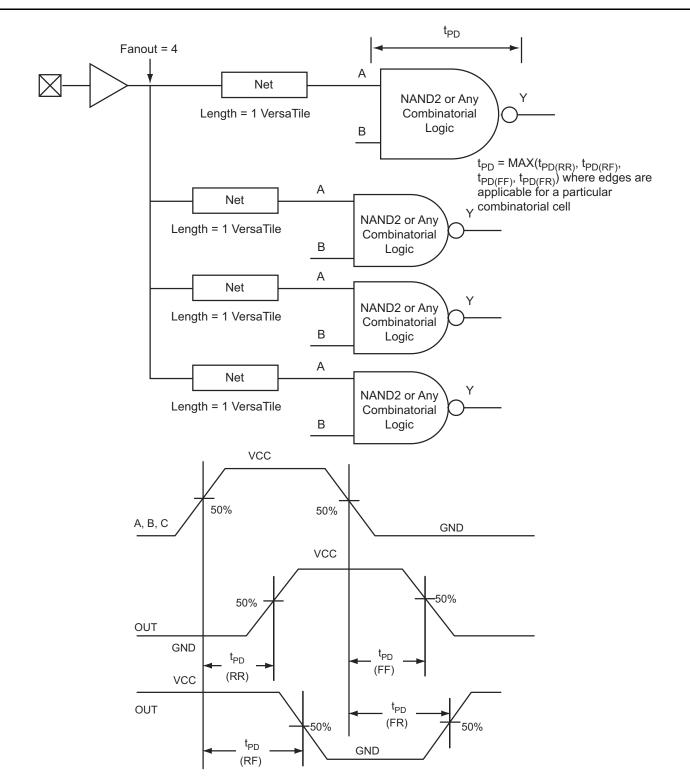


Figure 2-26 • Timing Model and Waveforms



Package Pin Assignments

	CS121
Pin Number	AGL060 Function
K10	VPUMP
K11	GDB1/IO47RSB0
L1	VMV1
L2	GNDQ
L3	IO65RSB1
L4	IO63RSB1
L5	IO61RSB1
L6	IO58RSB1
L7	IO57RSB1
L8	IO55RSB1
L9	GNDQ
L10	GDA0/IO50RSB0
L11	VMV1

Microsemi

Package Pin Assignments

	FG256		FG256		FG256
Pin Number	AGL400 Function	Pin Number	AGL400 Function	Pin Number	AGL400 Function
A1	GND	C7	IO20RSB0	E13	GBC2/IO62PDB1
A2	GAA0/IO00RSB0	C8	IO24RSB0	E14	IO65RSB1
A3	GAA1/IO01RSB0	C9	IO33RSB0	E15	IO52RSB0
A4	GAB0/IO02RSB0	C10	IO39RSB0	E16	IO66PDB1
A5	IO16RSB0	C11	IO45RSB0	F1	IO150NDB3
A6	IO17RSB0	C12	GBC0/IO54RSB0	F2	IO149NPB3
A7	IO22RSB0	C13	IO48RSB0	F3	IO09RSB0
A8	IO28RSB0	C14	VMV0	F4	IO152UDB3
A9	IO34RSB0	C15	IO61NPB1	F5	VCCIB3
A10	IO37RSB0	C16	IO63PDB1	F6	GND
A11	IO41RSB0	D1	IO151VDB3	F7	VCC
A12	IO43RSB0	D2	IO151UDB3	F8	VCC
A13	GBB1/IO57RSB0	D3	GAC2/IO153UDB3	F9	VCC
A14	GBA0/IO58RSB0	D4	IO06RSB0	F10	VCC
A15	GBA1/IO59RSB0	D5	GNDQ	F11	GND
A16	GND	D6	IO10RSB0	F12	VCCIB1
B1	GAB2/IO154UDB3	D7	IO19RSB0	F13	IO62NDB1
B2	GAA2/IO155UDB3	D8	IO26RSB0	F14	IO49RSB0
B3	IO12RSB0	D9	IO30RSB0	F15	IO64PPB1
B4	GAB1/IO03RSB0	D10	IO40RSB0	F16	IO66NDB1
B5	IO13RSB0	D11	IO46RSB0	G1	IO148NDB3
B6	IO14RSB0	D12	GNDQ	G2	IO148PDB3
B7	IO21RSB0	D13	IO47RSB0	G3	IO149PPB3
B8	IO27RSB0	D14	GBB2/IO61PPB1	G4	GFC1/IO147PPB3
B9	IO32RSB0	D15	IO53RSB0	G5	VCCIB3
B10	IO38RSB0	D16	IO63NDB1	G6	VCC
B11	IO42RSB0	E1	IO150PDB3	G7	GND
B12	GBC1/IO55RSB0	E2	IO08RSB0	G8	GND
B13	GBB0/IO56RSB0	E3	IO153VDB3	G9	GND
B14	IO44RSB0	E4	IO152VDB3	G10	GND
B15	GBA2/IO60PDB1	E5	VMV0	G11	VCC
B16	IO60NDB1	E6	VCCIB0	G12	VCCIB1
C1	IO154VDB3	E7	VCCIB0	G13	GCC1/IO67PPB1
C2	IO155VDB3	E8	IO25RSB0	G14	IO64NPB1
C3	IO11RSB0	E9	IO31RSB0	G15	IO73PDB1
C4	IO07RSB0	E10	VCCIB0	G16	IO73NDB1
C5	GAC0/IO04RSB0	E11	VCCIB0	H1	GFB0/IO146NPB3
C6	GAC1/IO05RSB0	E12	VMV1	H2	GFA0/IO145NDB3



Pin NumberAGL400 FunctionAA15NCAA16NCAA17NCAA18NCAA19NCAA20NCAA21VCCIB1AA22GNDAB1GND	_
AA16NCAA17NCAA18NCAA19NCAA20NCAA21VCCIB1AA22GNDAB1GND	
AA17NCAA18NCAA19NCAA20NCAA21VCCIB1AA22GNDAB1GND	
AA18NCAA19NCAA20NCAA21VCCIB1AA22GNDAB1GND	
AA19NCAA20NCAA21VCCIB1AA22GNDAB1GND	
AA20NCAA21VCCIB1AA22GNDAB1GND	
AA21 VCCIB1 AA22 GND AB1 GND	
AA22 GND AB1 GND	
AB1 GND	
AB2 GND	
AB3 VCCIB2	
AB4 NC	
AB5 NC	
AB6 IO121RSB2	
AB7 IO119RSB2	
AB8 IO114RSB2	
AB9 IO109RSB2	
AB10 NC	
AB11 NC	
AB12 IO104RSB2	
AB13 IO103RSB2	
AB14 NC	
AB15 NC	
AB16 IO91RSB2	
AB17 IO90RSB2	
AB18 NC	
AB19 NC	
AB20 VCCIB2	
AB21 GND	
AB22 GND	
B1 GND	
B2 VCCIB3	
B3 NC	
B4 NC	
B5 NC	
B6 NC	



Package Pin Assignments

FG484				
Pin Number	AGL400 Function			
H19	IO66PDB1			
H20	VCC			
H21	NC			
H22	NC			
J1	NC			
J2	NC			
J3	NC			
J4	IO150NDB3			
J5	IO149NPB3			
J6	IO09RSB0			
J7	IO152UDB3			
J8	VCCIB3			
J9	GND			
J10	VCC			
J11	VCC			
J12	VCC			
J13	VCC			
J14	GND			
J15	VCCIB1			
J16	IO62NDB1			
J17	IO49RSB0			
J18	IO64PPB1			
J19	IO66NDB1			
J20	NC			
J21	NC			
J22	NC			
K1	NC			
K2	NC			
K3	NC			
K4	IO148NDB3			
K5	IO148PDB3			
K6	IO149PPB3			
K7	GFC1/IO147PPB3			
K8	VCCIB3			
K9	VCC			
K10	GND			

FG484				
Pin Number	AGL600 Function			
H19	IO66PDB1			
H20	VCC			
H21	NC			
H22	NC			
J1	NC			
J2	NC			
J3	NC			
J4	IO166NDB3			
J5	IO168NPB3			
J6	IO167PPB3			
J7	IO169PDB3			
J8	VCCIB3			
J9	GND			
J10	VCC			
J11	VCC			
J12	VCC			
J13	VCC			
J14	GND			
J15	VCCIB1			
J16	IO62NDB1			
J17	IO64NPB1			
J18	IO65PPB1			
J19	IO66NDB1			
J20	NC			
J21	IO68PDB1			
J22	IO68NDB1			
K1	IO157PDB3			
K2	IO157NDB3			
K3	NC			
K4	IO165NDB3			
K5	IO165PDB3			
K6	IO168PPB3			
K7	GFC1/IO164PPB3			
K8	VCCIB3			
K9	VCC			
K10	GND			

FG484				
Pin Number	AGL1000 Function			
G5	IO222PDB3			
G6	GAC2/IO223PDB3			
G7	IO223NDB3			
G8	GNDQ			
G9	IO23RSB0			
G10	IO29RSB0			
G11	IO33RSB0			
G12	IO46RSB0			
G13	IO52RSB0			
G14	IO60RSB0			
G15	GNDQ			
G16	IO80NDB1			
G17	GBB2/IO79PDB1			
G18	IO79NDB1			
G19	IO82NPB1			
G20	IO85PDB1			
G21	IO85NDB1			
G22	NC			
H1	NC			
H2	NC			
H3	VCC			
H4	IO217PDB3			
H5	IO218PDB3			
H6	IO221NDB3			
H7	IO221PDB3			
H8	VMV0			
H9	VCCIB0			
H10	VCCIB0			
H11	IO38RSB0			
H12	IO47RSB0			
H13	VCCIB0			
H14	VCCIB0			
H15	VMV1			
H16	GBC2/IO80PDB1			
H17	IO83PPB1			
H18	IO86PPB1			

FG484				
Pin Number	AGL1000 Function			
K11	GND			
K12	GND			
K13	GND			
K14	VCC			
K15	VCCIB1			
K16	GCC1/IO91PPB1			
K17	IO90NPB1			
K18	IO88PDB1			
K19	IO88NDB1			
K20	IO94NPB1			
K21	IO98NDB1			
K22	IO98PDB1			
L1	NC			
L2	IO200PDB3			
L3	IO210NPB3			
L4	GFB0/IO208NPB3			
L5	GFA0/IO207NDB3			
L6	GFB1/IO208PPB3			
L7	VCOMPLF			
L8	GFC0/IO209NPB3			
L9	VCC			
L10	GND			
L11	GND			
L12	GND			
L13	GND			
L14	VCC			
L15	GCC0/IO91NPB1			
L16	GCB1/IO92PPB1			
L17	GCA0/IO93NPB1			
L18	IO96NPB1			
L19	GCB0/IO92NPB1			
L20	IO97PDB1			
L21	IO97NDB1			
L22	IO99NPB1			
M1	NC			
M2	IO200NDB3			

FG484		
Pin Number	AGL1000 Function	
M3	IO206NDB3	
M4	GFA2/IO206PDB3	
M5	GFA1/IO207PDB3	
M6	VCCPLF	
M7	IO205NDB3	
M8	GFB2/IO205PDB3	
M9	VCC	
M10	GND	
M11	GND	
M12	GND	
M13	GND	
M14	VCC	
M15	GCB2/IO95PPB1	
M16	GCA1/IO93PPB1	
M17	GCC2/IO96PPB1	
M18	IO100PPB1	
M19	GCA2/IO94PPB1	
M20	IO101PPB1	
M21	IO99PPB1	
M22	NC	
N1	IO201NDB3	
N2	IO201PDB3	
N3	NC	
N4	GFC2/IO204PDB3	
N5	IO204NDB3	
N6	IO203NDB3	
N7	IO203PDB3	
N8	VCCIB3	
N9	VCC	
N10	GND	
N11	GND	
N12	GND	
N13	GND	
N14	VCC	
N15	VCCIB1	
N16	IO95NPB1	

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IGLOO Low Power Flash FPGAs

Revision / Version	Changes	Page
Revision 3 (Feb 2008) Product Brief rev. 2	This document was updated to include AGL015 device information. QN68 is a new package offered in the AGL015. The following sections were updated: "Features and Benefits" "IGLOO Ordering Information" "Temperature Grade Offerings" "IGLOO Devices" Product Family Table Table 1 • IGLOO FPGAs Package Sizes Dimensions "AGL015 and AGL030" note The "Temperature Grade Offerings" table was updated to include M1AGL600. In the "IGLOO Ordering Information" table, the QN package measurements were updated to include both 0.4 mm and 0.5 mm.	N/A IV III
	In the "General Description" section, the number of I/Os was updated from 288 to 300.	1-1
Packaging v1.2	The "QN68" section is new.	4-25
Revision 2 (Jan 2008) Packaging v1.1	The "CS196" package and pin table was added for AGL125.	4-10
Revision 1 (Jan 2008) Product Brief rev. 1	The "Low Power" section was updated to change the description of low power active FPGA operation to "from 12 μ W" from "from 25 μ W." The same update was made in the "General Description" section and the "Flash*Freeze Technology" section.	l, 1-1
Revision 0 (Jan 2008)	This document was previously in datasheet Advance v0.7. As a result of moving to the handbook format, Actel has restarted the numbering.	N/A
Advance v0.7 (December 2007)	Table 1 • IGLOO Product Family, the "I/Os Per Package1" table, and the Temperature Grade Offerings table were updated to reflect the following: CS196 is now supported for AGL250; device/package support for QN132 is to be determined for AGL250; the CS281 package was added for AGL600 and AGL1000.	i, ii, iv
	Table 2 • IGLOO FPGAs Package Sizes Dimensions is new, and package sizes were removed from the "I/Os Per Package1" table.	ii
	The "I/Os Per Package1"table was updated to reflect 77 instead of 79 single- ended I/Os for the VG100 package for AGL030.	ii
	The "Timing Model" was updated to be consistent with the revised timing numbers.	2-20
	In Table 2-27 • Summary of Maximum and Minimum DC Input and Output Levels Applicable to Commercial and Industrial Conditions—Software Default Settings, T_J was changed to T_A in notes 1 and 2.	2-26
	All AC Loading figures for single-ended I/O standards were changed from Datapaths at 35 pF to 5 pF.	N/A
	The "1.2 V LVCMOS (JESD8-12A)" section is new.	2-74
	This document was previously in datasheet Advance v0.7. As a result of moving to the handbook format, Actel has restarted the version numbers. The new version number is Advance v0.1.	N/A
	Table 2-4 • IGLOO CCC/PLL Specification and Table 2-5 • IGLOO CCC/PLL Specification were updated.	2-19, 2-20